

Notic of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09/871,067	YAMAGUCHI ET AL.
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-3,944,330	03-1976	Tsunoda et al.	349/152
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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N					
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
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